

Linear Piezo Motor Actuator Combining Long Travel, Picometer Resolution and High Forces



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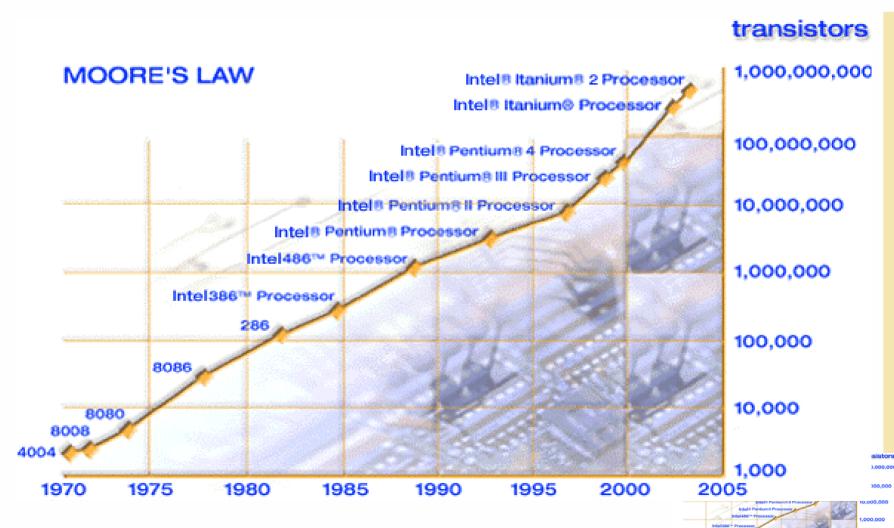
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The Problem: Moore's Law



The Problem: Moore's Law

- Moore's Law compresses IC linewidths and feature-sizes.
- Nanopositioning mechanisms embedded in frontend production and metrology tools have difficulties keeping up; they must provide
 10 to 1000x higher precision than feature size.
- Vibrations, position errors, drift need to be controlled to <0.1 nm (~atom diameter).
- Conventional nanopositioning systems have either high accuracy and short travel or do not provide the required stability and precision.



1,000,000,000

10,000,000

Requirements from Semiconductor Industry for Next Generation Actuators

- Resolution <0.1 nm + travel of several mm
- Keep position stable to nanometer level for a long time
- Lifetime several years minimum
- Stiff with high resonant frequency for fast response and low vibrations
- Must work in Vacuum, Helium, Magnetic Fields

Requirements can only be met with solid state piezoceramic actuators!

But How?



Piezo Technology Before NEXLINE®:

Piezo = Mission-critical Technology

Deployed throughout semiconductor fabrication, packaging & test

Actuators

 High Force, Speed, Resolution NEW: Ceramic Encapsulation (+Lifetime)

Flexure Positioners/Scanners

- <1 nm Resolution/Trajectory Accuracy</p>
- High-Speed Positioning and Scanning

Capacitive Position Feedback

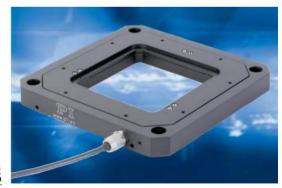
Sub-nm Resolution & Stability

Limitations (for some applications):

Either small travel range **OR** low stiffness No position hold with power off

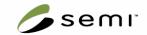


State-of-the-art PICMA® piezo actuators feature protective ceramic encapsulation



Low-profile, parallel-kinematics multi-axis

nanopositioning stage for nanometrology



NEXLINE®: Solves the Problem

- NEXLINE® Addresses the Drawbacks of Existing Nanopositioning Systems
- Unique Combination
 - Long Travel (No Basic Limitation)
 - <0.1 Nanometer Resolution</p>
 - High Bandwidth, High Force (to 500 N)
 - Very Compact & Stiff
 - Vacuum, Helium, UV compatible, Wide Temp. Range
 - Non-Magnetic Option (Electron Beam Compatible)
 - Auto Lock: nm-position hold @ 0V operating voltage:
 No Leakage Currents => no wear => 10 Year Lifetime



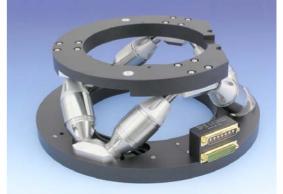


NEXLINE® Innovative Linear Actuators

Piezoelectric Hybrid Drive

- Flexible
 - Geometry, Size, Force, Travel
- Three Integration Levels
 - OEM Motor, Actuator, Multi-Axis Stage
- Applications:
 - Nanofabrication
 - Lithography
 - Alignment and Nanopositioning
 - Metrology / Testing
 - Repair Systems

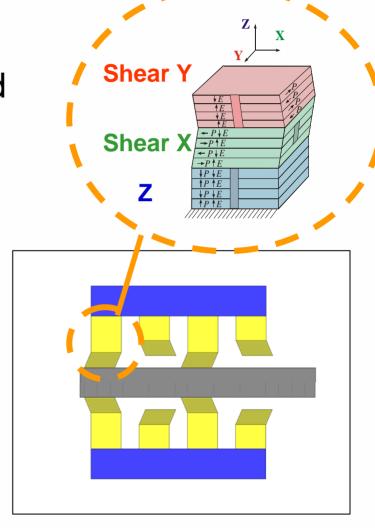




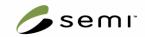


NEXLINE® Working Principle

- Combination of Shear and Linear Piezo Actuators
- Flexures for high guiding precision and zero friction
- Smart Digital Controller combines high resolution analog mode and long range step mode
- Compatible with different high resolution sensors

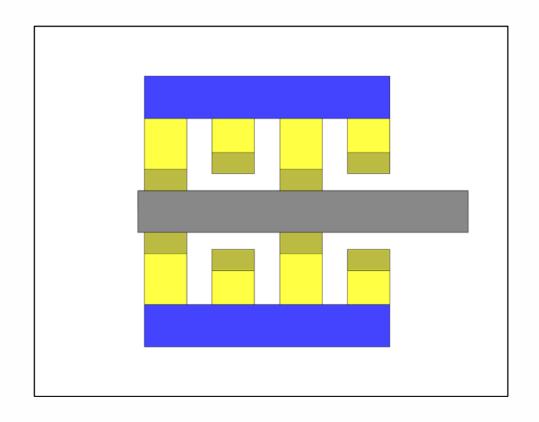




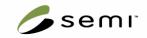


NEXLINE® Working Principle

- analog
- step
- mixed
- const. speed







NEXLINE® – Actuator Characteristics

N-215.00

• **Stroke**: 20 mm

Continuous Analog Mode: Resolution < 0.05 nm

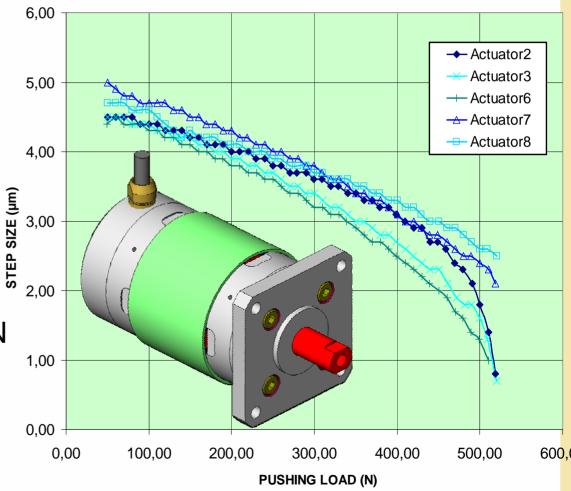
Range: to 4 µm

Step Mode:

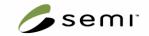
Step size: 5nm - 8µm

Blocking force: >500N

Slipping force: >600N

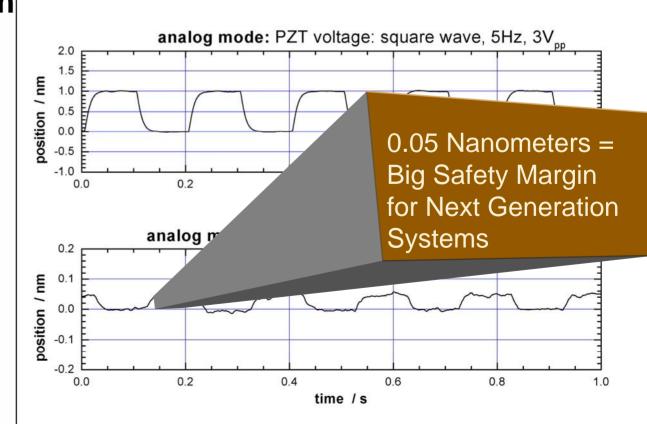






NEXLINE® – Actuator Characteristics

- A) Long range step mode
- B) <0.05 nm steps in analog mode



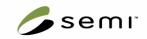
Value for Semiconductor Industry

NEXLINE® helps to increase resolution of steppers or scanners

 Improves the precision of projection systems by correcting errors caused by by vibrations, mechanical or thermal problems or other deficiencies

 Was specifically developed for the semiconductor industry and combines high resolution, compact design, high force, stiffness and lifetime

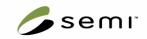




NEXLINE® Systems: What's next?

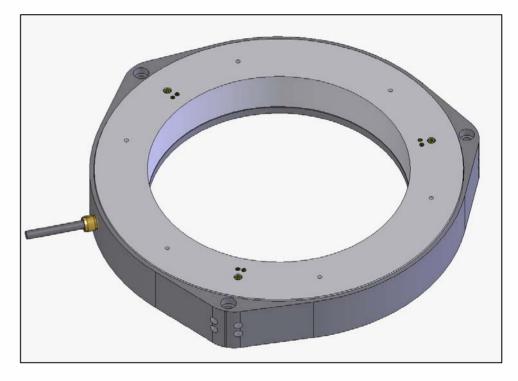
- NEXLINE® can be Integrated in Complex Multi-axis Positioning Systems
- Applications:
 - Wafer Chuck: Z/Tip/Tilt Stages
 - Positioning systems for nanoimprint lithography
 - Nanometrology systems



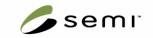


High Load Z-Tip/Tilt Wafer Stage

- Z-stroke: 1.3 mm
- Tip/Tilt: +/- 4mrad
- Max. Load >50 kg
- Closed loop with internal incremental sensor







Nonmagnetic 6-DOF Hexapod

Low Profile, Six-Axis Nanopositioning System

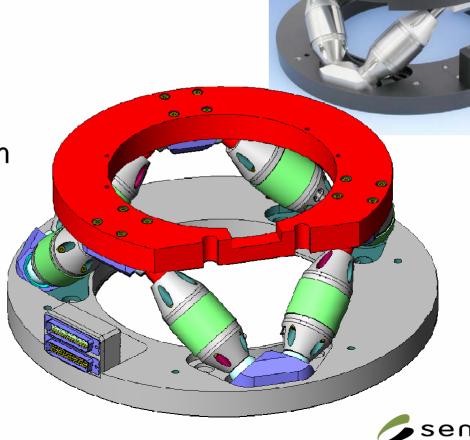
8" Aperture

Load 50kg

Low Profile: 140mm

Translation XYZ: 10mm

Rotation all axes: 6 °



NEXLINE® Technology Summary

- Increases performance of production and metrology tools
- Proven, novel technology
- Has been successfully used in semiconductor applications
- Addresses challenges of emerging lithographies (e.g., EUV, immersion, nanoimprint)
- Overcomes limitations of classical nanopositioning systems
- Very flexible: from OEM-actuators to 6 DOF systems





